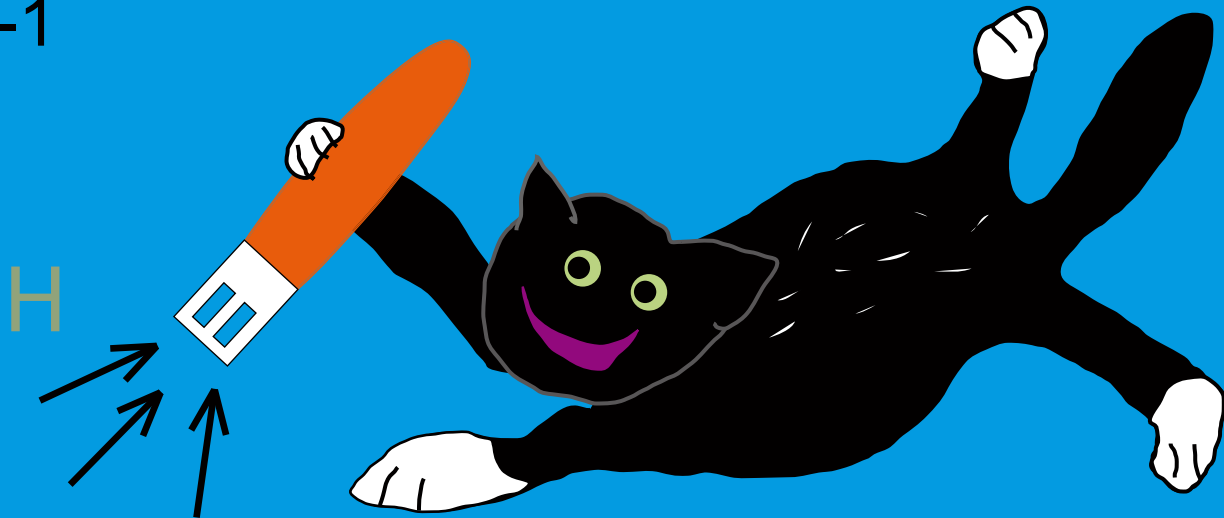


# Near-Field Probe 20 GHz

SX-R 20-1



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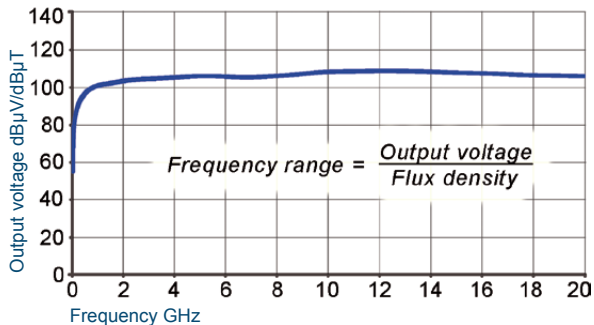
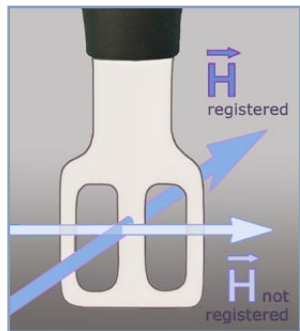
# SX-R 20-1 set

## Near-Field Probe

- High resolution
- Emission analysis
- Up to 20 GHz



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The SX-R 20-1 set consists of a passive near-field probe for measuring magnetic fields with a high clock frequency up to 20 GHz on electronic assemblies and ICs during the development stage.

An electronic assembly's field orientation and field distribution can be detected through specific use of the near-field probe.

All the different SX near-field probes are small and handy. They have a current attenuating sheath and, therefore, are electrically shielded. They can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input.